

## **MOSFET**

### OptiMOS<sup>™</sup> Power-Transistor, 60 V

#### **Features**

- Optimized for high performance SMPS, e.g. sync. rec.
  100% avalanche tested
  Superior thermal resistance

- N-channel
- Qualified according to JEDEC<sup>1)</sup> for target applications
  Pb-free lead plating; RoHS compliant
  Halogen-free according to IEC61249-2-21



Parameter	Value	Unit	
<b>V</b> <sub>DS</sub>	60	V	
R <sub>DS(on),max</sub>	4.0	mΩ	
I <sub>D</sub>	101	A	
Qoss	32	nC	
Q <sub>G</sub> (0V4.5V)	18	nC	











Type / Ordering Code	Package	Marking	Related Links
BSZ040N06LS5	PG-TSDSON-8 FL	040N06L	-

# OptiMOS<sup>™</sup> Power-Transistor, 60 V BSZ040N06LS5



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# OptiMOS<sup>™</sup> Power-Transistor, 60 V **BSZ040N06LS5**



# 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 Maximum ratings

Damamastan	0	Values				N
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	- - -	- - -	101 64 17	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =60K/W <sup>2)</sup>
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	404	Α	<i>T</i> <sub>C</sub> =25 °C
Avalanche energy, single pulse <sup>4)</sup>	<b>E</b> AS	-	-	117	mJ	$I_{\rm D}$ =20 A, $R_{\rm GS}$ =25 $\Omega$
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-
Power dissipation	P <sub>tot</sub>	-	-	69 2.1	W	T <sub>C</sub> =25 °C T <sub>A</sub> =25 °C, R <sub>thJA</sub> =60 K/W <sup>2)</sup>
Operating and storage temperature	$T_{\rm j},~T_{\rm stg}$	-55	-	150	°C	IEC climatic category; DIN IEC 68-1: 55/150/56

#### 2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition
Thermal resistance, junction - case	R <sub>thJC</sub>	-	1.1	1.8	K/W	-
Device on PCB, minimal footprint	R <sub>thJA</sub>	_	-	62	K/W	-
Device on PCB, 6 cm <sup>2</sup> cooling area <sup>2)</sup>	R <sub>thJA</sub>	-	-	60	K/W	-

<sup>&</sup>lt;sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature at 25°C. For higher case temperature please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.  $^{2)}$  Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

<sup>&</sup>lt;sup>4)</sup> See Diagram 13 for more detailed information

# OptiMOS<sup>™</sup> Power-Transistor, 60 V BSZ040N06LS5



#### 3 Electrical characteristics

at T<sub>j</sub>=25 °C, unless otherwise specified

**Table 4** Static characteristics

Parameter.	0		Values			N	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	60	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	V <sub>GS(th)</sub>	1.1	1.7	2.3	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =36 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	1 100	μA	V <sub>DS</sub> =60 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =60 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	3.3 4.4	4.0 5.6	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =20 A V <sub>GS</sub> =4.5 V, I <sub>D</sub> =10 A	
Gate resistance <sup>1)</sup>	R <sub>G</sub>	-	1.6	2.4	Ω	-	
Transconductance	<b>g</b> fs	32	65	-	S	$ V_{DS}  > 2 I_D R_{DS(on)max}, I_D = 20 A$	

Table 5 Dynamic characteristics

Domester	Sumah al	Values			I I mid	Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance <sup>1)</sup>	Ciss	-	2400	3100	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =30 V, <i>f</i> =1 MHz
Output capacitance <sup>1)</sup>	Coss	-	500	650	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =30 V, <i>f</i> =1 MHz
Reverse transfer capacitance <sup>1)</sup>	C <sub>rss</sub>	-	25	44	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =30 V, <i>f</i> =1 MHz
Turn-on delay time	$t_{ m d(on)}$	-	8.5	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	4.6	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	25.6	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	t <sub>f</sub>	-	4.8	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Table 6 Gate charge characteristics<sup>2)</sup>

B	0	Values			T	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	Q <sub>gs</sub>	-	6.6	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	3.9	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate to drain charge <sup>1)</sup>	$Q_{ m gd}$	-	5.3	8.0	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Switching charge	Q <sub>sw</sub>	-	8.0	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total <sup>1)</sup>	Qg	-	18	22	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate plateau voltage	V <sub>plateau</sub>	-	2.7	-	V	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total, sync. FET <sup>1)</sup>	Q <sub>g(sync)</sub>	-	32	42	nC	V <sub>DS</sub> =0.1 V, V <sub>GS</sub> =0 to 10 V
Output charge <sup>1)</sup>	Qoss	-	32	42	nC	V <sub>DD</sub> =30 V, V <sub>GS</sub> =0 V

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test  $^{2)}$  See "Gate charge waveforms" for parameter definition

# OptiMOS<sup>TM</sup> Power-Transistor, 60 V BSZ040N06LS5

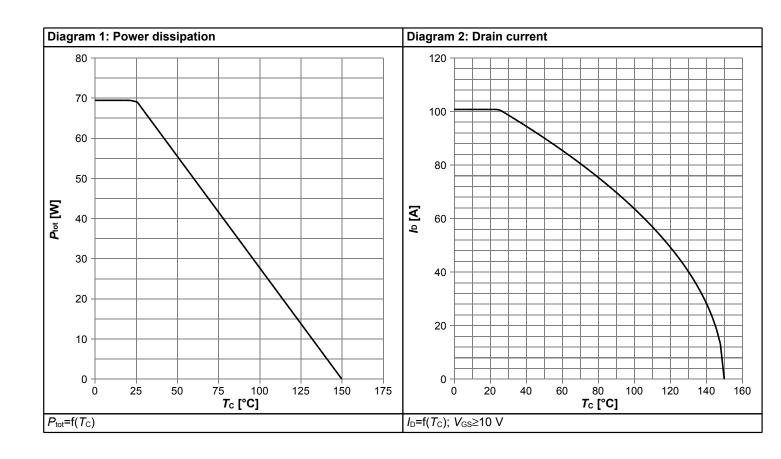


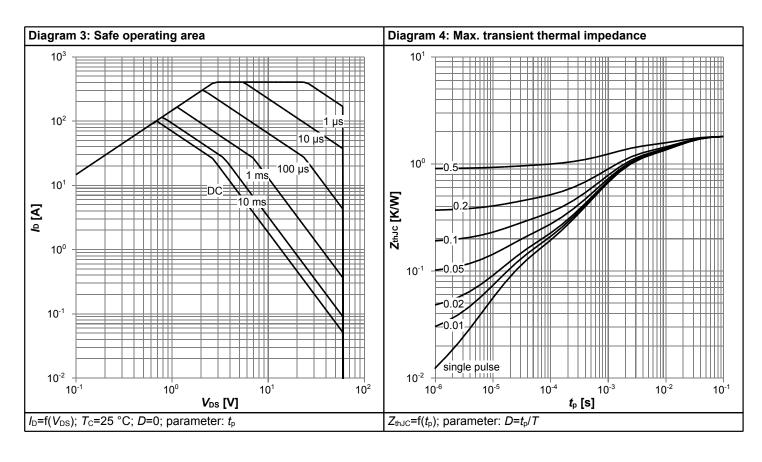
#### Table 7 Reverse diode

Davamatav	Cymphal		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	58	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	404	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode forward voltage	<b>V</b> <sub>SD</sub>	-	0.80	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =20 A, T <sub>j</sub> =25 °C	
Reverse recovery time <sup>1)</sup>	<i>t</i> <sub>rr</sub>	-	24	48	ns	V <sub>R</sub> =30 V, I <sub>F</sub> =20 A, di <sub>F</sub> /dt=100 A/μs	
Reverse recovery charge <sup>1)</sup>	Qrr	-	11	22	nC	V <sub>R</sub> =30 V, I <sub>F</sub> =20 A, di <sub>F</sub> /dt=100 A/μs	

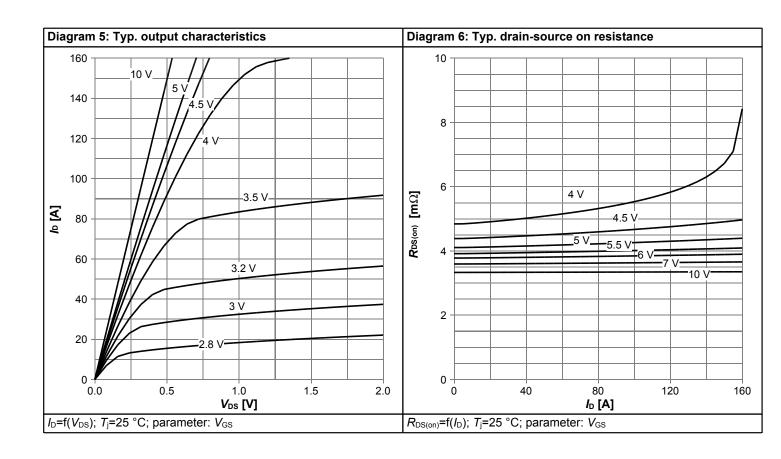


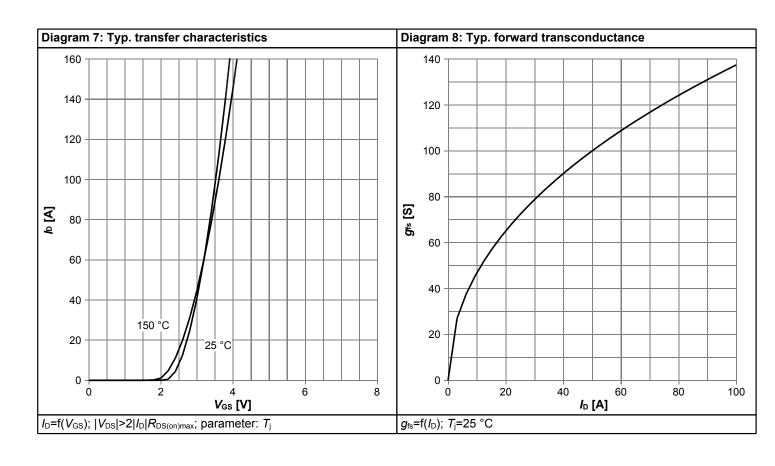
## 4 Electrical characteristics diagrams



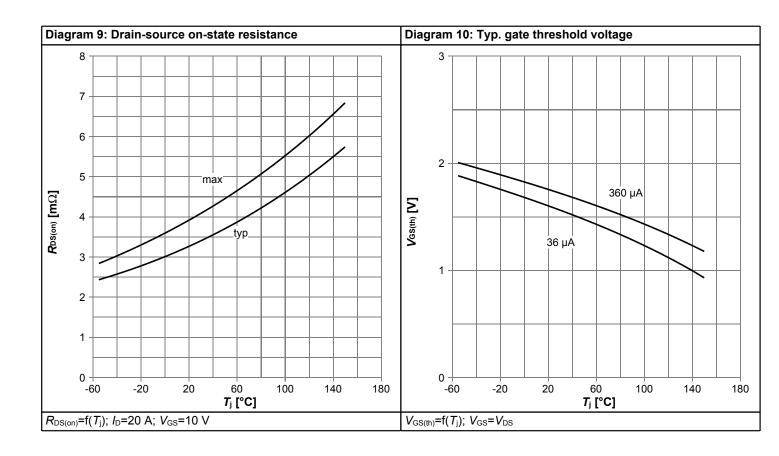


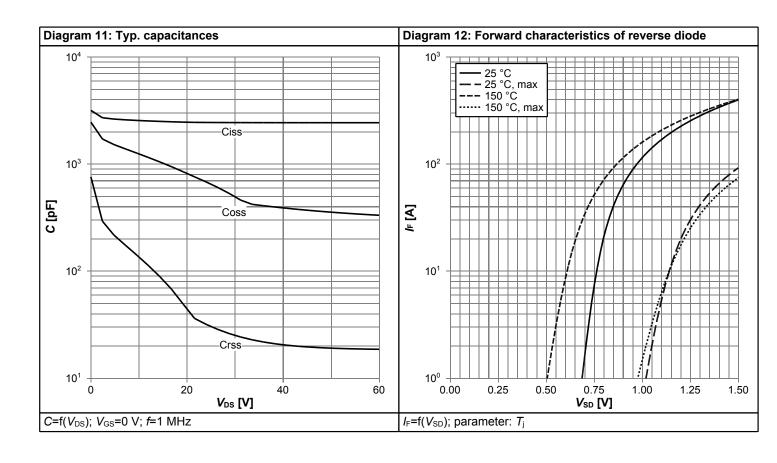




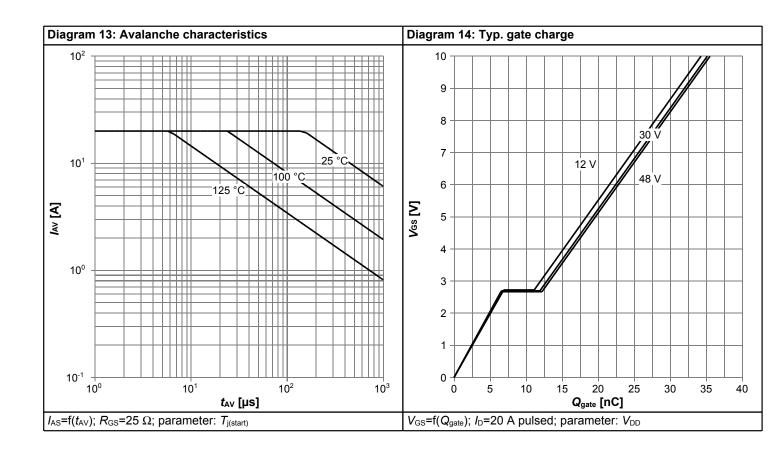


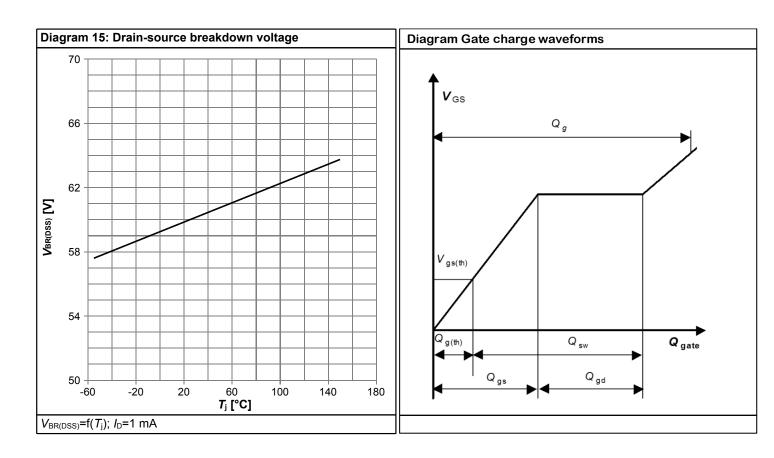






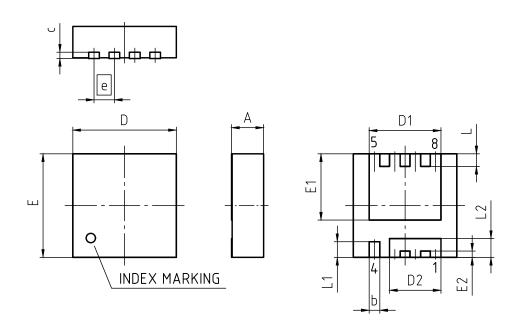








# 5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TSDS	SON-8-U03		
REVISION: 03	DATE:	20.10.2020		
DIMENSIONS	MILLIN	IETERS		
DIMENSIONS	MIN.	MAX.		
Α	0.90	1.10		
b	0.24	0.44		
С	(0.	20)		
D	3.20	3.40		
D1	2.19	2.39		
D2	1.54	1.74		
E	3.20	3.40		
E1	2.01	2.21		
E2	0.10	0.30		
е	0.65			
L	0.30	0.50		
L1	0.40	0.60		
L2	0.50	0.70		
aaa	0.0	06		

Figure 1 Outline PG-TSDSON-8 FL, dimensions in mm

### OptiMOS<sup>™</sup> Power-Transistor, 60 V BSZ040N06LS5



#### **Revision History**

BSZ040N06LS5

Revision: 2021-02-11, Rev. 2.3

Previous Revision

Tevida Nevidion						
Revision	Date	Subjects (major changes since last revision)				
2.0	2016-04-21	Release of final version				
2.1	2016-08-10	Update in Qrr and trr				
2.2	2020-05-18	Update Max Current Rating				
2.3	2021-02-11	Update package drawing				

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